
**Lasers and laser-related equipment —
Test methods for laser beam
widths, divergence angles and beam
propagation ratios —**

**Part 2:
General astigmatic beams**

*Lasers et équipements associés aux lasers — Méthodes d'essai des
largeurs du faisceau, angles de divergence et facteurs de limite de
diffraction —*

Partie 2: Faisceaux astigmatiques généraux

ISO 11146-2:2021

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Foreword

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This second edition cancels and replaces the first edition (ISO 11146-2:2005), which has been technically revised. The main changes compared to the previous edition are as follows:

- The terms and definitions were harmonized with the new ISO 11145.
- The "principal axes" were defined more thoroughly and named as x' and y' . Quantities related to the principal axes coordinate system refer to this definition and use x' and y' in their indices.
- The requirements for the integration range for the determination of the second order moments have been relaxed.

A list of all parts in the ISO 11146 series can be found on the ISO website.

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